



## IECQ Certificate of Conformity Hazardous Substance Process Management

IECQ Certificate No.:	IECQ-H ULTW 14.0007	Issue No.:	6	Status:	Current
Supersedes:	<a href="#">IECQ-H ULTW 14.0007 Issue 5</a>	Issue Date:	2023/07/21	Org Issue:	2014/07/24
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Applicable to:

- European Directive 2011/65/EU ("RoHS – Restriction of the use Of certain Hazardous Substances") in electrical and electronic equipment. Including all published amendments
- Other Identified Hazardous Substances

### PHOENIX SILICON INTERNATIONAL CORPORATION

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Taiwan

The organization has developed and implemented Hazardous Substance Process Management procedures and related processes which have been assessed and found to comply with the applicable requirements for IECQ HSPM organization approval which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-5 "IECQ Hazardous Substances Process Management" of the IEC Quality Assessment System for Electronic Components (IECQ), and with respect to the IECQ Specification:

- IECQ QC 080000:2017 - Hazardous Substance Process Management System Requirements

This Certificate is applicable to all electronic components, assemblies, related materials and processes for the following scope of activities:

The manufacture of wafers.

Issued by the Certification Body: DQS Group - DQS Taiwan Inc.

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Feng Yuan Dist., Taichung City  
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Authorized person:  
Rock Chang



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.

This certificate and any schedule(s) may only be reproduced in full.

This certificate is not transferable and remains the property of the issuing IECQ CB.

The Status and authenticity of this certificate may be verified by visiting [www.iecq.org](http://www.iecq.org)